

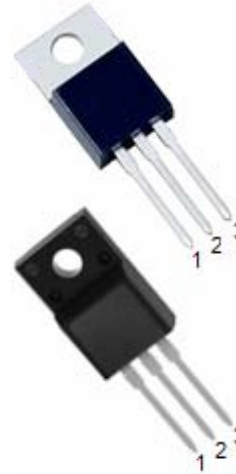
Industrial model	Popular name	Package identification	Packing method	Quantity per tube	Quantity per box	Quantity per carton
SPT10N80 SPF10N80	10N80 10N80	T: TO-220AB F: TO-220F-3L	TUBE	50/tube	1Kpcs/box	5Kpcs

■ Features

Originative New Design
 Superior Avalanche Rugged Technology
 Robust Gate Oxide Technology
 Very Low Intrinsic Capacitances
 Excellent Switching Characteristics
 Unrivalled Gate Charge: 13.5nC(Typ.)
 Extended Safe Operating Area
 Lower $R_{DS(ON)}$ 1Ω(Typ.) @ $V_{GS}=10V$
 100% Avalanche Tested
 Package: TO-220AB & TO-220F-3L

$I_D=10A$
 $BV_{DSS}=800V$
 $R_{DS(on)}=0.8\Omega$

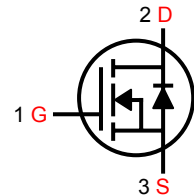
SPF/T10N80 Series Pin Assignment



3-Lead Plastic TO-220AB
 Package Code: T
 Pin 1: Gate
 Pin 2 & Tab: Drain
 Pin 3: Source

3-Lead Plastic TO-220F-3L
 Package Code: F
 Pin 1: Gate
 Pin 2: Drain
 Pin 3: Source

Series Symbol:



■ ABSOLUTE MAXIMUM RATINGS ($T_C=25^\circ C$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	800	V
Gate-Source Voltage		V_{GSS}	± 30	V
Continuous Drain Current ($T_C = 25^\circ C$)		I_D	10	A
Pulsed Drain Current (Note 2)		I_{DM}	40	A
Avalanche Current (Note 2)		I_{AR}	10	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	920	mJ
	Repetitive (Note 2)	E_{AR}	24	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.0	V/ns
Power Dissipation	TO-220AB	P_D	240	W
	TO-220F-3L		36	
Linear Derating Factor above $T_C = 25^\circ C$	TO-220AB		1.92	$^\circ C/W$
	TO-220F-3L		0.288	
Junction Temperature		T_J	150	$^\circ C$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ C$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=17.3mH$, $I_{AS}=10A$, $V_{DD}=50V$, $R_G=25\Omega$, Starting $T_J=25^\circ C$

4. $I_{SD} \leq 10 A$, $di/dt \leq 200A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ C$.

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220AB	θ_{JA}	40	$^\circ C/W$
	TO-220F-3L		62.5	
Junction to Case	TO-220AB	θ_{JC}	0.52	$^\circ C/W$
	TO-220F-3L		3.47	

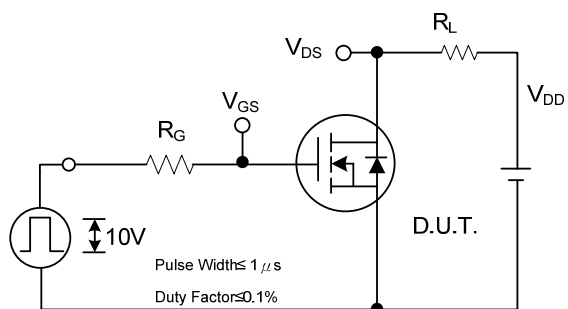
■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0 V, I _D =250 μA	800			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =800V, V _{GS} =0 V			10	μA
		V _{DS} =640V, T _C =125°C			100	
Gate-Body Leakage Current	I _{GSS}	V _{DS} =0 V, V _{GS} = ±30 V			±100	nA
Breakdown Voltage Temperature Coefficient	ΔBV _{DSS} /ΔT _J	I _D =250 μA, Referenced to 25°C		0.98		mV/°C
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250 μA	3.0		5.0	V
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} = 10 V, I _D = 5.0 A		0.8	1	Ω
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1MHz		2150	2800	pF
Output Capacitance	C _{OSS}			180	230	pF
Reverse Transfer Capacitance	C _{RSS}			15	20	pF
SWITCHING PARAMETERS						
Turn-ON Delay Time	t _{D(ON)}	V _{DD} =400V, I _D =10.0A, R _G =25Ω(Note 1,2)		50	110	ns
Turn-ON Rise Time	t _R			130	270	
Turn-OFF Delay Time	t _{D(OFF)}			90	190	
Turn-OFF Fall-Time	t _F			80	170	
Total Gate Charge	Q _G	V _{DS} =640V, V _{GS} =10V, I _D =10.0A (Note 1,2)		45	58	nC
Gate Source Charge	Q _{GS}			13.5		
Gate Drain Charge	Q _{GD}			17		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Drain-Source Diode Forward Voltage	V _{SD}	I _S =10.0 A, V _{GS} =0V			1.4	V
Maximum Continuous Drain-Source Diode Forward Current	I _S				10.0	A
Maximum Pulsed Drain-Source Diode Forward Current	I _{SM}				40.0	
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _F /dt = 100 A/μs,		730		ns
Reverse Recovery Charge	Q _{RR}	I _S = 10.0 A (Note 1)		10.9		nC

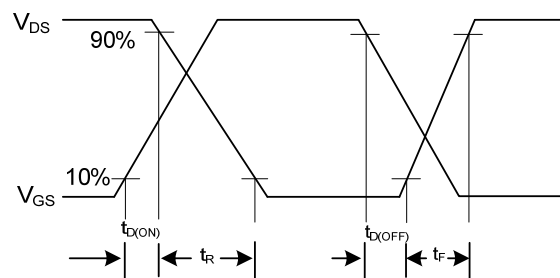
Notes: 1. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.

2. Independent of operating temperature.

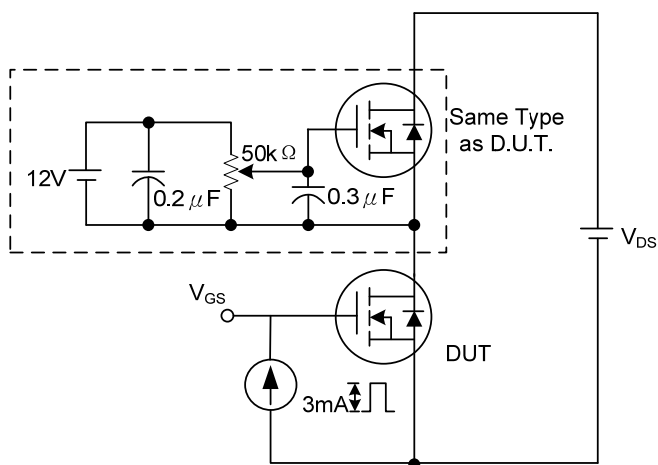
■ TEST CIRCUIT



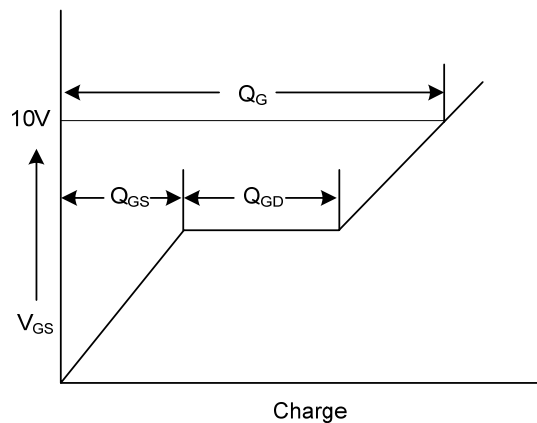
Switching Test Circuit



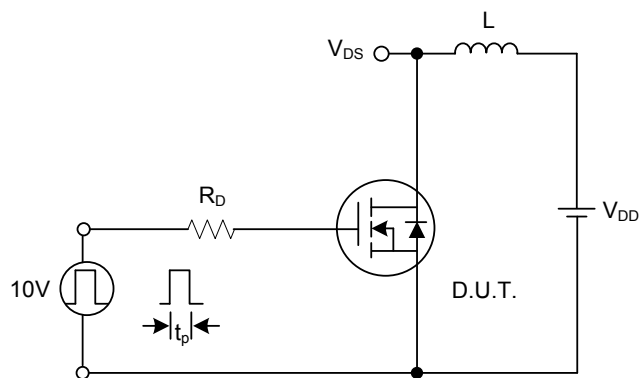
Switching Waveforms



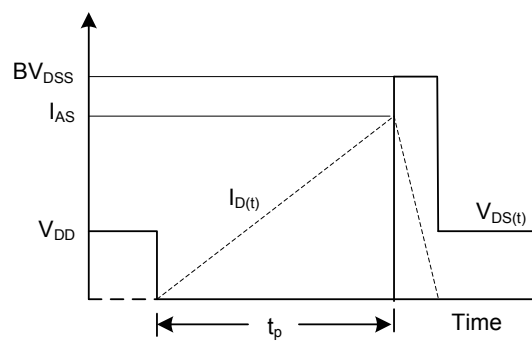
Gate Charge Test Circuit



Gate Charge Waveform

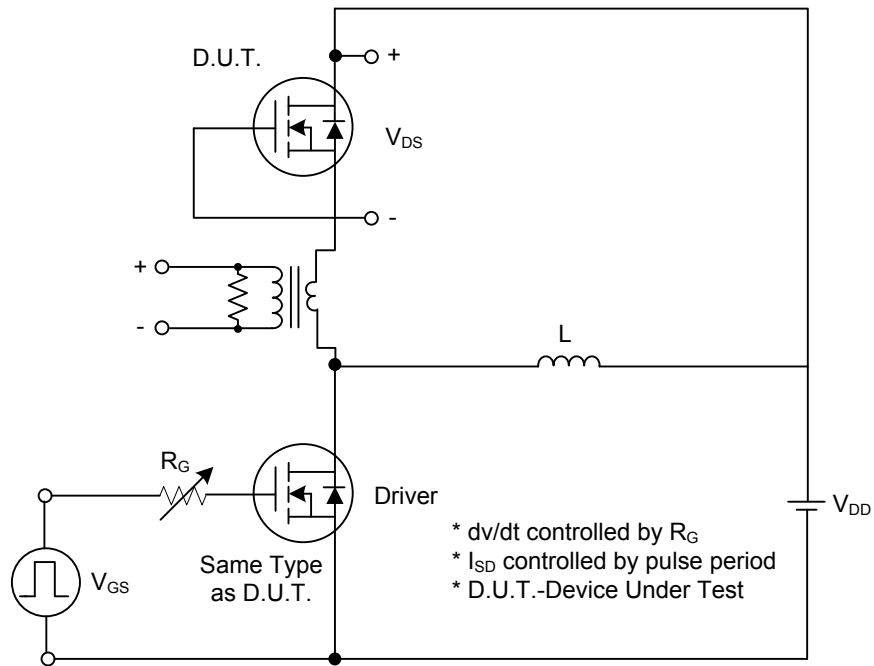


Unclamped Inductive Switching Test Circuit

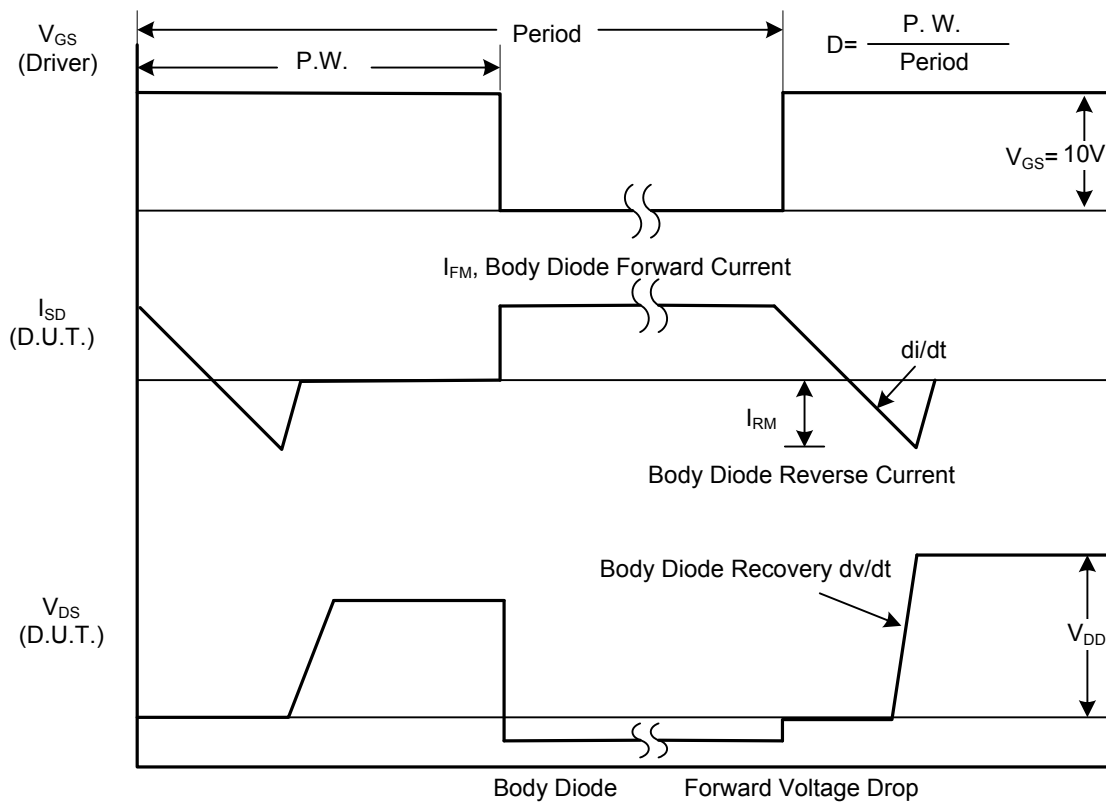


Unclamped Inductive Switching Waveforms

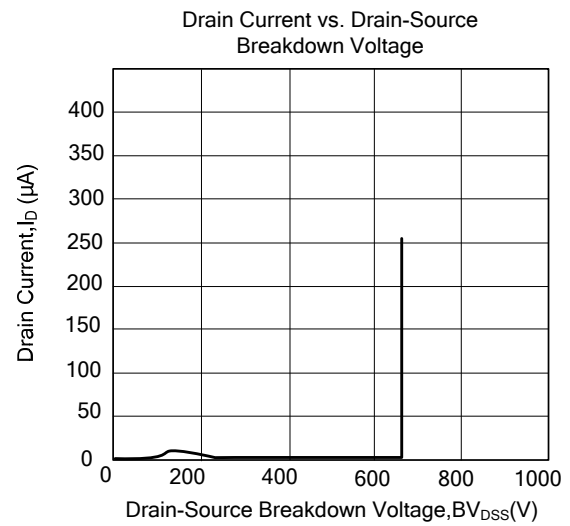
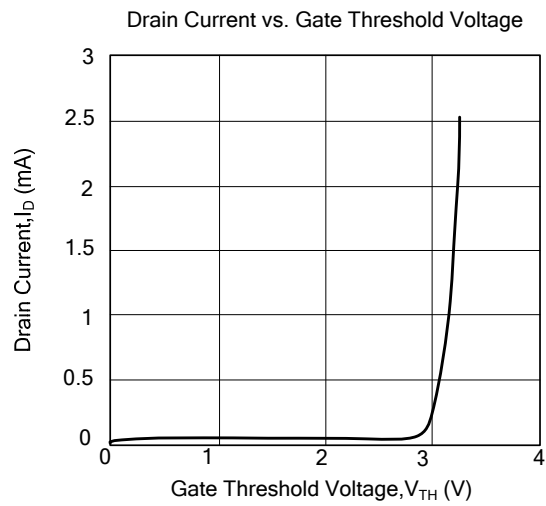
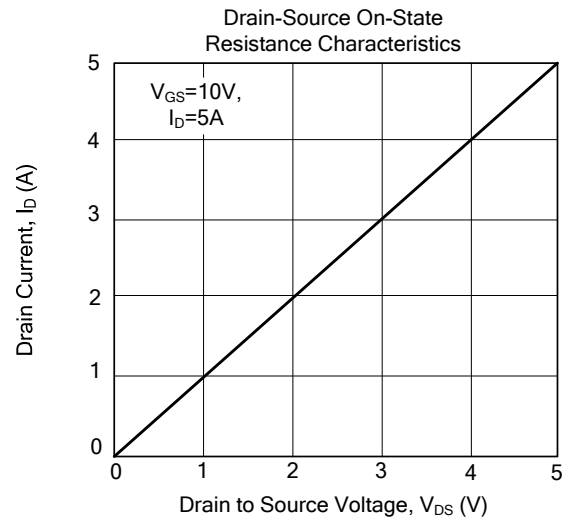
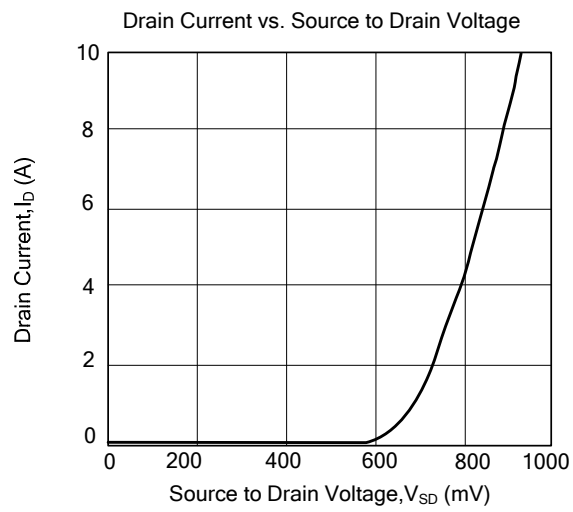
■ TEST CIRCUIT(Cont.)



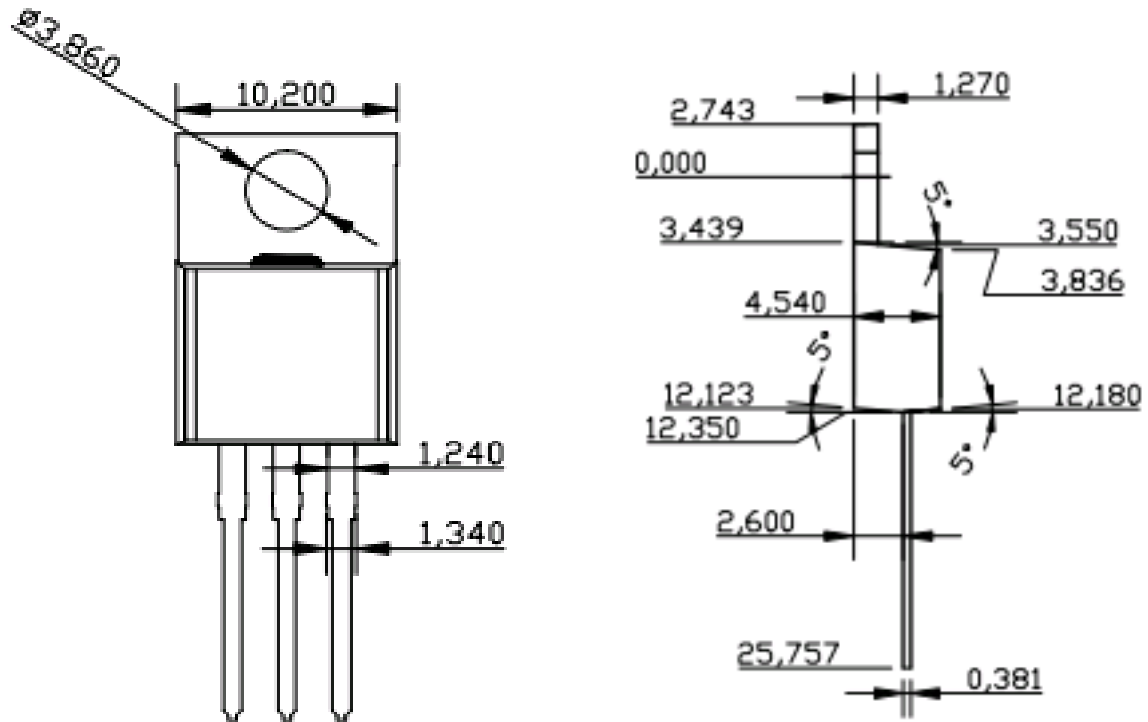
Peak Diode Recovery dv/dt Test Circuit



■ TYPICAL CHARACTERISTICS



TO-220-3L PACKAGE OUTLINE DIMENSIONS



TO- 220F- 3L PACKAGE OUTLINE DIMENSIONS

